

## ABSTRACT OF THE DISCLOSURE

5           A method for measuring a thickness of a non-conductive coating on a semi-conductive substrate includes placing a pair of conducting plates in contact with the non-conductive coating. A capacitance value of the non-conductive coating in combination with the semi-conductive component is measured using a capacitance meter. The measured capacitance value of the non-conductive coating in  
10 combination with the semi-conductive component is then used to determine an independent capacitance value of the non-conductive coating. The thickness of the non-conductive coating is directly related to the independent capacitance value of the non-conductive coating.

15